

Search Notes**Application/Control No.**

10/033,746

Examiner

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Applicant(s)/Patent under Reexamination

CHAN ET AL.

Art Unit

2162

SEARCHED

Class	Subclass	Date	Examiner
707	1-10	6/23/2005	IW
707	100-104.1	6/23/2005	IW
707	200-206	6/23/2005	IW
709	217-219	6/23/2005	IW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US-PGPUB, EPO , JPO, DERWENT, IBM_TDB), IEEE, ACM, NPL	6/23/2005	IW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner